

# PRODUCT/PROCESS CHANGE NOTIFICATION

PCN CRP/12/7016 Notification Date 02/06/2012

Qualification of additional suppliers of trays for LQFP 14x14x1.4mm and PQFP 28x28 packages

#### **Table 1. Change Implementation Schedule**

Forecasted implementation date for change	07-May-2012
Forecasted availabillity date of samples for customer	30-Jan-2012
Forecasted date for <b>STMicroelectronics</b> change Qualification Plan results availability	30-Jan-2012
Estimated date of changed product first shipment	07-May-2012

#### **Table 2. Change Identification**

Product Identification (Product Family/Commercial Product)	Trays for LQFP 14x14x1.4mm and PQFP 28x28 packages
Type of change	Packing
Reason for change	supply chain robustness
Description of the change	New suppliers of trays have been qualified. The key dimensions of these new trays are identical to the ones provided by the current supplier ITW. In addition, trays remain stackable independently of the supplier.
Product Line(s) and/or Part Number(s)	See attached
Description of the Qualification Plan	See attached
Change Product Identification	Change Identification through QA number
Manufacturing Location(s)	Please Refer To The Description Of The Change

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Customer Part numbers list	
Qualification Plan results	

Customer Acknowledgement of Receipt	PCN CRP/12/7016
Please sign and return to STMicroelectronics Sales Office	Notification Date 02/06/2012
□ Qualification Plan Denied	Name:
□ Qualification Plan Approved	Title:
	Company:
☐ Change Denied	Date:
□ Change Approved	Signature:
Remark	

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### **DOCUMENT APPROVAL**

Name	Function		
Sibille, Marie-Helene	Corporate Quality Manager		
Low, Patrick	Process Owner		

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## Qualification of additional suppliers of trays for LQFP 14x14x1.4mm and PQFP 28x28 packages

#### WHAT:

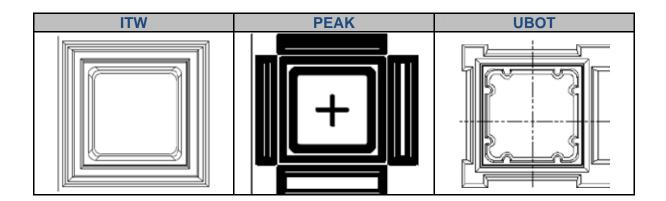
New suppliers of trays have been qualified. The key dimensions of these new trays are identical to the ones provided by the current supplier ITW. In addition, trays remain stackable independently of the supplier.

The trays impacted are:

- Trays for LQFP 14x14x1.4mm packages: the new qualified suppliers are PEAK and UBOT
- Trays for PQFP 28x28 packages: the new qualified supplier is PEAK

It concerns the products whose testing and finishing plants are located in Malta, Malaysia and at our sub-contractors

The only change being introduced is a visual difference as indicated below:



#### WHY:

The purpose of the introduction of new sources is to make robust the supply chain of trays.

#### WHEN:

Unless specific customer requirements, these new suppliers will be introduced at minimum 3 months after the delivery of this notification.

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#### HOW:

The following documents introduce the qualification results for:

- PEAK supplier for TQFP 14x14x1.4 Tray in Malta plant
- PEAK supplier for TQFP 14x14x1.4 Tray in Malaysia plant
- UBOT supplier for TQFP 14x14x1.4 Tray in Malta plant
  UBOT supplier for TQFP 14x14x1.4 Tray in Malaysia plant
  PEAK supplier for PQFP 28x28 Tray in Malta plant

### **Qualification of UBOT TQFP 14x14x1.4 Tray**

#### **Objective:**

To evaluate UBOT (UQ14141.40615XCU) trays as tray 2<sup>nd</sup> source for QFP 14x14x1.4 device packing application at PTM Muar.

#### **Tray Information:**

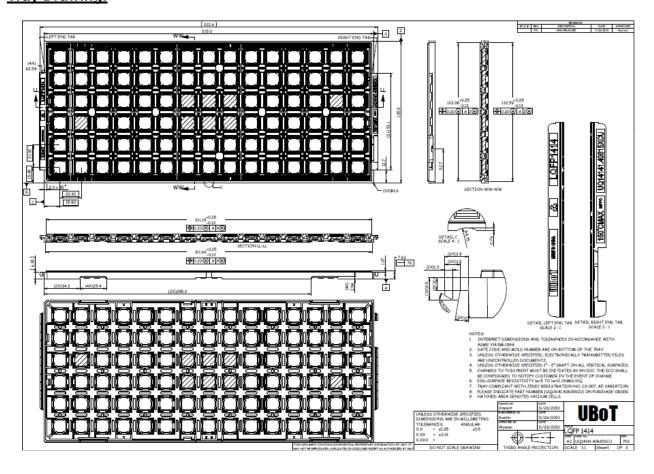
Supplier : UBOT

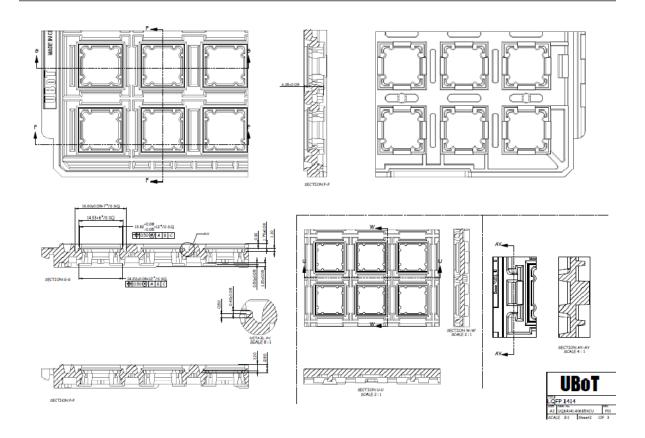
Supplier Part No : UQ14141.40615XCU

Tray ADCS Reference No: 0004320

Material Code : 3CP20430/1 (Green/Blue Insert)

#### **Tray Drawing:**





1. Visual Inspection Report:
Result: Accepted. No Tray Abnormalities.

Items	Visual Inspection	Yes	No	Quantities	Remarks
1	Chip/Crack		Х	N/A	
2	Align with ST	Х		N/A	
	Specification	^		IN/A	
3	Tray Matrix	Χ		N/A	
4	Full Fence	Χ		N/A	
_	Meet JEDEC	Х		N/A	
5	Standard requirement	^		IN/A	
6	Contain stain or		Х	N/A	
0	foreign material		^	IN/A	
7	Others		Х		
'	(Please defined)		^		

#### 2. Baking Tests (Bakeable trays only)

**Result: Accepted** 

#### 2.1. <u>3 Cycle Baking</u> Result: Accepted

#### 2.1.1. Methodology

- i) Sample: 10 trays.
- ii) Duration: 24 hrs for each cycle. After each cycle, the tray must leave at production environment for a minimum of 1 hr before starting the second baking.
- iii) Temperature: 125 deg.C (Refer to specification number 0033575)
- iv) Trays must strap using Velcro or PP (Polypropylene) belt. Strapping refers to specification number 0056593.
- v) Baking can be carrying out without units.
- vi) Measure the tray warpage after the 3<sup>rd</sup> cycle on all 6 corners as indicated in specification 8080190.
- vii) The warpage should not be > 0.5mm for new tray.

#### 2.1.2. <u>Results</u>

Tray warpage after 3 cycle baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.05	0.05	0.00	0.05	0.05	0.00
Sample 2	0.05	0.05	0.05	0.00	0.05	0.00
Sample 3	0.05	0.05	0.00	0.05	0.00	0.00
Sample 4	0.00	0.00	0.00	0.00	0.05	0.05
Sample 5	0.05	0.05	0.05	0.00	0.00	0.05
Sample 6	0.05	0.05	0.00	0.05	0.05	0.00
Sample 7	0.05	0.00	0.00	0.00	0.00	0.00
Sample 8	0.05	0.00	0.00	0.05	0.00	0.00
Sample 9	0.00	0.00	0.05	0.00	0.00	0.05
Sample 10	0.00	0.00	0.05	0.05	0.00	0.05

All readings are within limits.

#### 2.2. Single Bake

Result: Accepted

#### 2.2.1. Methodology

- i) Sample: 6 pieces of single trays not stacked.
- ii) Duration 48 hrs.
- iii) Temperature: Base on the temperature mark on the tray (150 deg.C)
- iv) Without unit and without strapping
- v) After single bake, the tray warpage is measured after leaving the tray to cool to room temperature.
- vi) Measure the tray warpage on all 6 corners as indicated in specification 8080190

#### 2.2.2. <u>Results</u>

Tray warpage after Single Baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.25	0.00	0.15	0.05	0.00	0.20
Sample 2	0.30	0.15	0.10	0.20	0.25	0.10
Sample 3	0.25	0.00	0.00	0.05	0.15	0.05
Sample 4	0.10	0.25	0.00	0.05	0.15	0.00
Sample 5	0.05	0.00	0.10	0.00	0.25	0.05
Sample 6	0.25	0.05	0.00	0.05	0.00	0.00

The trays were also checked for the below items:

Items	Result
Any melting point on tray	NO
Any shrinkage on overall length	NO
Any shrinkage on overall thickness	NO
Any shrinkage on pocket dimension	NO
Maximum warpage from 6 corners should not be more than 0.76mm	0.30mm

#### 3. Drop Test

Result: Accepted

#### 3.1. <u>Methodology</u>

The drop test was performed with the packing methodology described in specification number 0056593. The drop test was carried out according to methodology described in specification number 7416802.

#### 3.2. Results

Drop Test Sequence	Scanning Results for: i) Coplan ii) Standoff iii) Pitch	Results
ABC	0 rejects	Pass
DEF	0 rejects	Pass
GHI	0 rejects	Pass

Note: Drop Test Sequence ABC refers to Face A, Edge B & Corner C.

Inspection items	Sample size	Reject quantity for ABC	Reject quantity for DEF	Reject quantity for GHI
Unit chip	540 units	0/540	0/540	0/540
Unit stuck	540 units	0/540	0/540	0/540
Unit misplace	540 units	0/540	0/540	0/540
Chip trays	7 trays	0/7	0/7	0/7

#### 4. ESD Measurements

Result: Accepted.

#### 4.1. Equipment

- i) Prostat PRS-801 Resistance Meter
- ii) Prostat PRV-913 Microprobe Verifier
- iii) Prostat probes PRF-922A-B and PRF914
- iv) Prostat Psychrometer PHT-771

#### 4.2. <u>Methodology</u>

A sample of six trays were used to measure the surface resistance. Each tray was tested at six different points. The accepted limits for the trays should be within 1x10exp5<Rs<1x10exp11.

Every reading was recorded as shown in the table below.

#### 4.3. Results

TESTS	TRAY	SURF	ACE RESI	STANCE N	IEASUREN	IENTS (oh	ms)
TESTS	SAMPLES	Point 1	Point 2	Point 3	Point 4	Point 5	Point 6
	Sample 1	1.5E+08	1.2E+08	1.4E+08	1.4E+08	1.2E+08	1E+08
	Sample 2	1.2E+08	2.3E+08	2E+08	9E+08	1.3E+08	1.3E+09
SURFACE	Sample 3	1.1E+08	1E+08	1.5E+08	1.2E+08	1.2E+08	1.3E+08
RESISTANCE TEST	Sample 4	1.2E+08	6.6E+08	2.8E+08	2.9E+08	4.5E+08	1.2E+09
	Sample 5	1E+08	6.1E+08	2.9E+08	3.5E+08	1.7E+08	1.3E+09
	Sample 6	1.4E+08	2.3E+08	2.7E+08	2.5E+08	9.3E+08	1.4E+09
SURFACE RESISTANCE	Sample 1 (before scratching)	1.5E+08					
AFTER SCRATCHING	Sample 1 (After scratching)	1.2E+08					

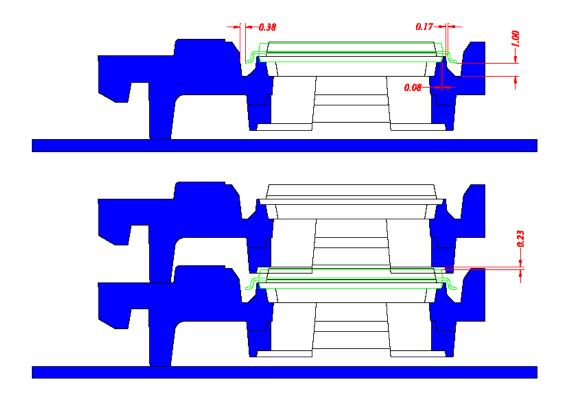
All measurements are within ST Specification Limits.

## 5. Workability Test: Result: Accepted

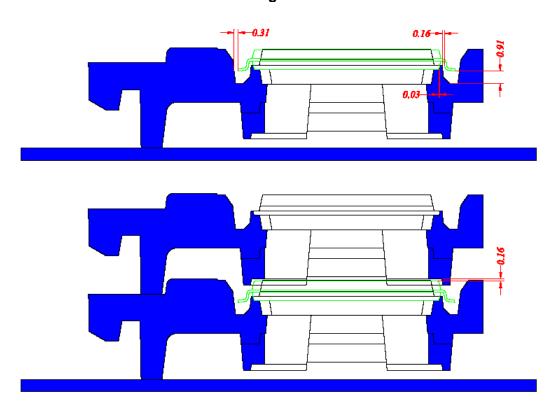
Process Step	Machine	Samples size	Rejection criteria	Result
Cropping	ASM	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Tester	Synax 141	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Finishing	STI	540 units	Bend lead, package crack, tray is jamming when machine running	Pass

6. <u>FIT Analysis</u> Result: Accepted

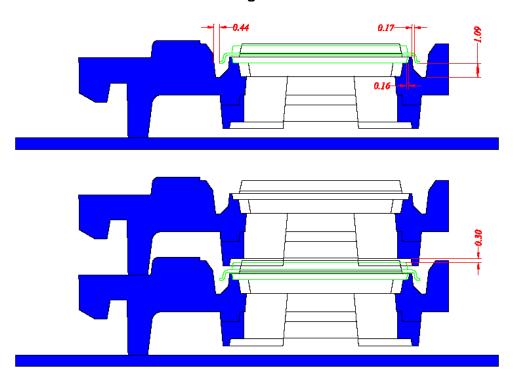
#### **Nominal Case:**



#### **Minimum Pocket vs Maximum Package:**



### **Maximum Pocket vs Minimum Package:**



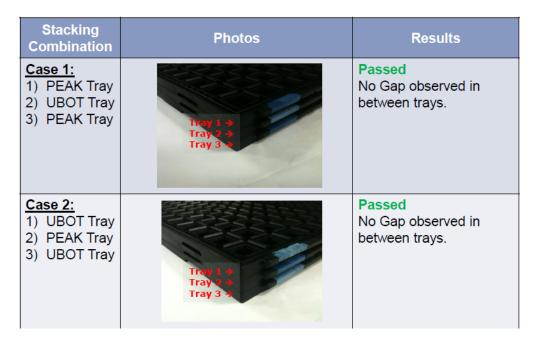
#### 7. Additional Items:

#### 7.1. Stackability Validation



A Tray	B Tray	Stackability
UBot	ITW	Yes
ITW	UBot	Yes

(i) UBOT trays are stackable with current source, ITW trays.



(ii) UBOT trays are stackable with alternative source, PEAK trays.

#### **Conclusion:**

With the above qualification results, UBOT (UQ14141.40615XCU) tray passed all ST tray qualification requirements, thus, qualified for production use.

### **Qualification of UBOT TQFP 14x14x1.4 Tray**

#### **Objective:**

To evaluate UBOT (UQ14141.40615XCU) trays as tray 2<sup>nd</sup> source for QFP 14x14x1.4 device packing application at PTM Malta.

#### **Tray Information:**

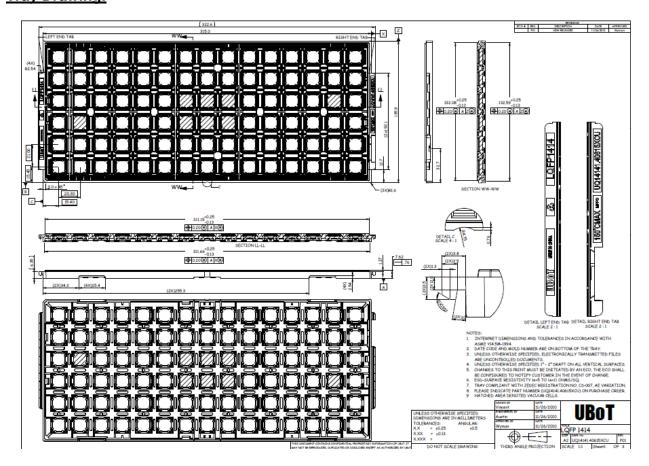
Supplier : UBOT

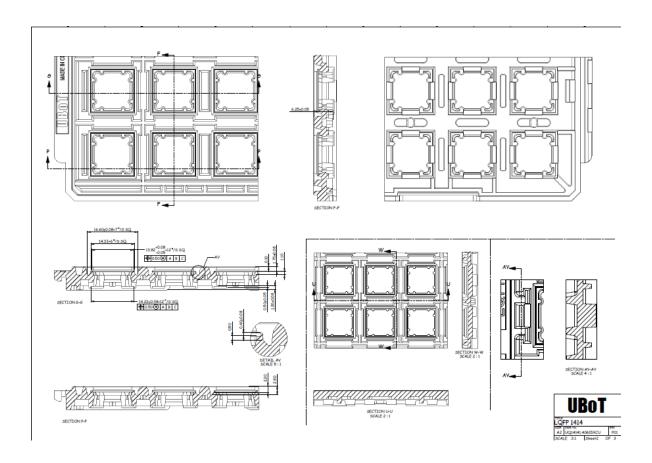
Supplier Part No : UQ14141.40615XCU

Tray ADCS Reference No: 0004320

Material Code : 3CP20430/1 (Green/Blue Insert)

#### **Tray Drawing:**





1. Visual Inspection Report:
Result: Accepted. No Tray Abnormalities.

Items	Visual Inspection	Yes	No	Quantities	Remarks
1	Chip/Crack		Х	N/A	
2	Align with ST	Χ		N/A	
	Specification			14/7 (	
3	Tray Matrix	Χ		N/A	
4	Full Fence	Χ		N/A	
5	Meet JEDEC	Х		N/A	
5	Standard requirement	^		IN/A	
6	Contain stain or		X	N/A	
O	foreign material		^	IN/A	
7	Others		Х		
	(Please defined)		^		

#### 2. Baking Tests (Bakeable trays only)

**Result: Accepted** 

#### 2.1. <u>3 Cycle Baking</u> Result: Accepted

#### 2.1.1. Methodology

- i) Sample: 10 trays.
- ii) Duration: 24 hrs for each cycle. After each cycle, the tray must leave at production environment for a minimum of 1 hr before starting the second baking.
- iii) Temperature: 125 deg.C (Refer to specification number 0033575)
- iv) Trays must strap using Velcro or PP (Polypropylene) belt. Strapping refers to specification number 0056593.
- v) Baking can be carrying out without units.
- vi) Measure the tray warpage after the 3<sup>rd</sup> cycle on all 6 corners as indicated in specification 8080190.
- vii) The war page should not be > 0.5mm for new tray.

#### 2.1.2. **Results**

Tray warpage after 3 cycle baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.00	0.25	0.10	0.05	0.05	0.05
Sample 2	0.05	0.25	0.10	0.05	0.15	0.00
Sample 3	0.05	0.20	0.15	0.05	0.05	0.05
Sample 4	0.10	0.15	0.05	0.05	0.15	0.05
Sample 5	0.10	0.25	0.10	0.05	0.25	0.05
Sample 6	0.05	0.25	0.05	0.00	0.20	0.00
Sample 7	0.10	0.25	0.15	0.05	0.15	0.05
Sample 8	0.05	0.25	0.15	0.05	0.00	0.00
Sample 9	0.00	0.25	0.15	0.10	0.00	0.05
Sample 10	0.10	0.25	0.15	0.05	0.00	0.05

All readings are within limits.

#### 2.2. Single Bake

**Result: Accepted** 

#### 2.2.1. Methodology

- i) Sample: 6 pieces of single trays not stacked.
- ii) Duration 48 hrs.
- iii) Temperature: Base on the temperature mark on the tray (150 deg.C)
- iv) Without unit and without strapping
- v) After single bake, the tray warpage is measured after leaving the tray to cool to room temperature.
- vi) Measure the tray warpage on all 6 corners as indicated in specification 8080190

#### 2.2.2. <u>Results</u>

Tray warpage after Single Baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.00	0.05	0.00	0.05	0.25	0.05
Sample 2	0.00	0.05	0.00	0.00	0.00	0.00
Sample 3	0.00	0.00	0.00	0.05	0.05	0.00
Sample 4	0.00	0.00	0.10	0.15	0.05	0.05
Sample 5	0.05	0.40	0.20	0.05	0.05	0.05
Sample 6	0.10	0.30	0.15	0.05	0.15	0.05

The trays were also checked for the below items:

Items	Result
Any melting point on tray	NO
Any shrinkage on overall length	NO
Any shrinkage on overall thickness	NO
Any shrinkage on pocket dimension	NO
Maximum warpage from 6 corners	0.4mm
should not be more than 0.76mm	0.411111

#### 3. Drop Test

Result: Accepted

#### 3.1. Methodology

The drop test was performed with the packing methodology described in specification number 0056593. The drop test was carried out according to methodology described in specification number 7416802.

#### 3.2. Results

Drop Test Sequence	Scanning Results for: i) Coplan ii) Standoff iii) Pitch	Results
ABC	0 rejects	Pass
DEF	0 rejects	Pass
GHI	0 rejects	Pass

Note: Drop Test Sequence ABC refers to Face A, Edge B & Corner C.

Inspection items	Sample size	Reject quantity for ABC	Reject quantity for DEF	Reject quantity for GHI
Unit chip	540 units	0/540	0/540	0/540
Unit stuck	540 units	0/540	0/540	0/540
Unit misplace	540 units	0/540	0/540	0/540
Chip trays	7 trays	0/7	0/7	0/7

#### 4. ESD Measurements

Result: Accepted.

#### 4.1. Equipment

- i) Prostat PRS-801 Resistance Meter
- ii) Prostat PRV-913 Microprobe Verifier
- iii) Prostat probes PRF-922A-B and PRF914
- iv) Prostat Psychrometer PHT-771

#### 4.2. Methodology

A sample of six trays were used to measure the surface resistance. Each tray was tested at six different points. The accepted limits for the trays should be within 1x10exp5<Rs<1x10exp11.

Every reading was recorded as shown in the table below.

#### 4.3. Results

TECTO	TRAY	SUR	FACE RES	SISTANCE	MEASURE	MENTS(of	nms)
TESTS	SAMPLES	Point 1	Point 2	Point 3	Point 4	Point 5	Point 6
	Sample 1	5.0e06	3.3e06	3.3e07	2.0e06	2.4e07	1.9e07
	Sample 2	1.1e07	1.5e06	1.3e06	5.1e06	1.1e07	4.8e08
SURFACE	Sample 3	1.1e08	1.7e07	8.8e08	4.5e06	4.1e07	6.1e07
RESISTANCE TEST	Sample 4	1.2e07	1.9e06	8.2e08	2.6e07	1.9e08	6.1e07
	Sample 5	2.7e08	3.6e07	1.5e06	4.2e08	3.9e07	6.5e07
	Sample 6	3.7e08	2.4e11	2.3e06	1.5e06	6.0e08	1.3e08
SURFACE RESISTANCE	Sample 1 (before scratching)	3.0e10					
AFTER SCRATCHING	Sample 1 (After scratching)	2.6e10					

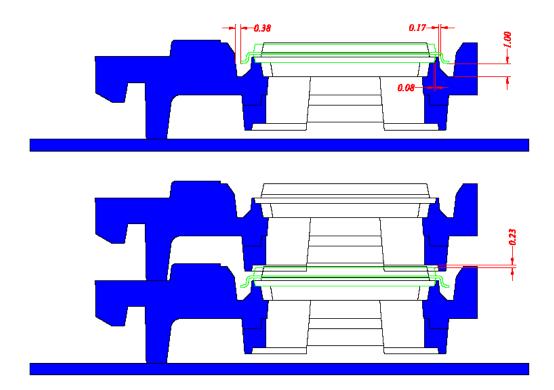
All measurements are within ST Specification Limits.

## 5. Workability Test: Result: Accepted

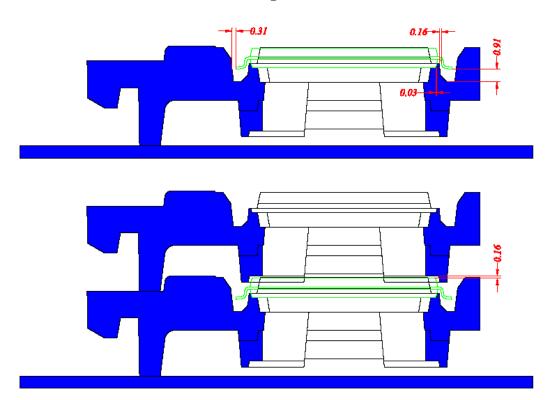
Process Step	Machine	Samples size	Rejection criteria	Result
Cropping	ASM MP209	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Tester	Multitest 9510	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Finishing	Hexa Whizz	540 units	Bend lead, package crack, tray is jamming when machine running	Pass

6. <u>FIT Analysis</u> Result: Accepted

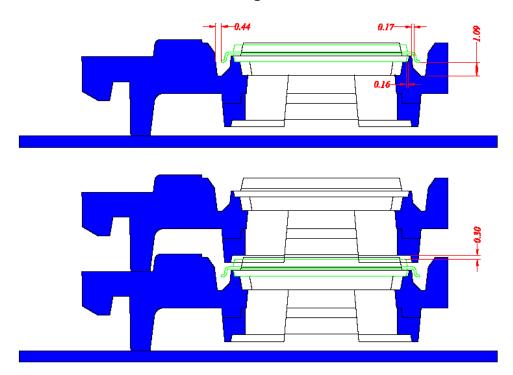
#### **Nominal Case:**



### **Minimum Pocket vs Maximum Package:**



### **Maximum Pocket vs Minimum Package:**



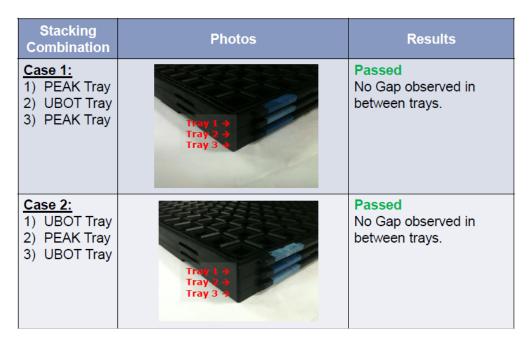
#### 7. Additional Items:

#### 7.1. Stackability Validation



A Tray	B Tray	Stackability
UBot	ITW	Yes
ITW	UBot	Yes

(i) UBOT trays are stackable with current source, ITW trays.



(ii) UBOT trays are stackable with alternative source, PEAK trays.

#### **Conclusion:**

With the above qualification results, UBOT (UQ14141.40615XCU) tray passed all ST tray qualification requirements, thus, qualified for production use.

#### **Qualification of PEAK TQFP 14x14x1.4 Tray**

#### **Objective:**

To evaluate PEAK (ND 1414 1.4 0615 6 REV.FbL2) trays as tray 2<sup>nd</sup> source for QFP 14x14x1.4 device packing application at PTM Muar.

#### **Tray Information:**

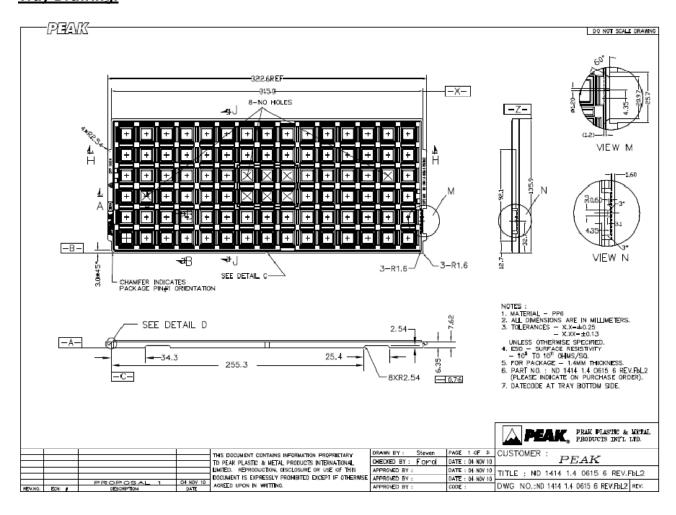
Supplier : PEAK

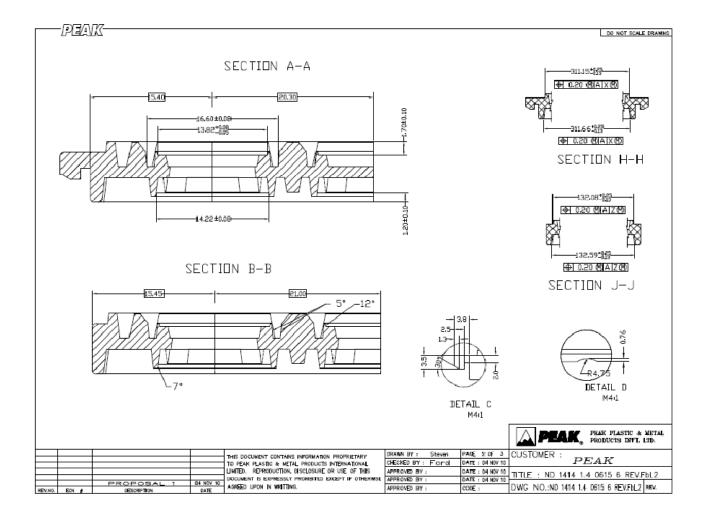
Supplier Part No : ND 1414 1.4 0615 6 REV.FbL2

Tray ADCS Reference No: 0004320

Material Code : 3CP20430/1 (Green/Blue Insert)

#### **Tray Drawing:**





### 1. Visual Inspection Report:

Result: Accepted. No Tray Abnormalities.

Items	Visual Inspection	Yes	No	Quantities	Remarks
1	Chip/Crack		Χ	N/A	
2	Align with ST Specification	X		N/A	
3	Tray Matrix	Χ		N/A	
4	Full Fence	Χ		N/A	
5	Meet JEDEC Standard requirement	X		N/A	
6	Contain stain or foreign material		X	N/A	
7	Others (Please defined)		X		

#### 2. Baking Tests (Bakeable trays only)

**Result: Accepted** 

#### 2.1. <u>3 Cycle Baking</u> Result: Accepted

#### 2.1.1. Methodology

- i) Sample: 10 trays.
- ii) Duration: 24 hrs for each cycle. After each cycle, the tray must leave at production environment for a minimum of 1 hr before starting the second baking.
- iii) Temperature: 125 deg.C (Refer to specification number 0033575)
- iv) Trays must strap using Velcro or PP (Polypropylene) belt. Strapping refers to specification number 0056593.
- v) Baking can be carrying out without units.
- vi) Measure the tray warpage after the 3<sup>rd</sup> cycle on all 6 corners as indicated in specification 8080190.
- vii) The warpage should not be > 0.5mm for new tray.

#### 2.1.2. <u>Results</u>

Tray warpage after 3 cycle baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.05	0.25	0.15	0.00	0.00	0.10
Sample 2	0.05	0.15	0.15	0.00	0.25	0.05
Sample 3	0.00	0.20	0.20	0.15	0.05	0.15
Sample 4	0.25	0.05	0.05	0.05	0.25	0.10
Sample 5	0.25	0.00	0.20	0.10	0.05	0.10
Sample 6	0.10	0.00	0.10	0.00	0.10	0.10
Sample 7	0.05	0.05	0.00	0.20	0.05	0.00
Sample 8	0.10	0.20	0.00	0.00	0.10	0.10
Sample 9	0.15	0.00	0.05	0.10	0.05	0.20
Sample 10	0.05	0.25	0.10	0.00	0.10	0.00

All readings are within limits.

#### 2.2. Single Bake

Result: Accepted

#### 2.2.1. Methodology

- i) Sample: 6 pieces of single trays not stacked.
- ii) Duration 48 hrs.
- iii) Temperature: Base on the temperature mark on the tray (150 deg.C)
- iv) Without unit and without strapping
- v) After single bake, the tray warpage is measured after leaving the tray to cool to room temperature.
- vi) Measure the tray warpage on all 6 corners as indicated in specification 8080190

#### 2.2.2. <u>Results</u>

Tray warpage after Single Baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.00	0.25	0.25	0.20	0.00	0.00
Sample 2	0.25	0.70	0.45	0.30	0.50	0.00
Sample 3	0.20	0.25	0.00	0.40	0.20	0.35
Sample 4	0.60	0.35	0.30	0.15	0.30	0.15
Sample 5	0.20	0.00	0.15	0.45	0.10	0.30
Sample 6	0.15	0.35	0.70	0.15	0.70	0.10

The trays were also checked for the below items:

Items	Result
Any melting point on tray	NO
Any shrinkage on overall length	NO
Any shrinkage on overall thickness	NO
Any shrinkage on pocket dimension	NO
Maximum warpage from 6 corners should not be more than 0.76mm	0.7mm

#### 3. Drop Test

Result: Accepted

#### 3.1. <u>Methodology</u>

The drop test was performed with the packing methodology described in specification number 0056593. The drop test was carried out according to methodology described in specification number 7416802.

#### 3.2. Results

Drop Test Sequence	Scanning Results for: i) Coplan ii) Standoff iii) Pitch	Results
ABC	0 rejects	Pass
DEF	0 rejects	Pass
GHI	0 rejects	Pass

Note: Drop Test Sequence ABC refers to Face A, Edge B & Corner C.

Inspection items	Sample size	Reject quantity for ABC	Reject quantity for DEF	Reject quantity for GHI
Unit chip	540 units	0/540	0/540	0/540
Unit stuck	540 units	0/540	0/540	0/540
Unit misplace	540 units	0/540	0/540	0/540
Chip trays	7 trays	0/7	0/7	0/7

#### 4. ESD Measurements

Result: Accepted.

#### 4.1. Equipment

- i) Prostat PRS-801 Resistance Meter
- ii) Prostat PRV-913 Microprobe Verifier
- iii) Prostat probes PRF-922A-B and PRF914
- iv) Prostat Psychrometer PHT-771

#### 4.2. <u>Methodology</u>

A sample of six trays were used to measure the surface resistance. Each tray was tested at six different points. The accepted limits for the trays should be within 1x10exp5<Rs<1x10exp11.

Every reading was recorded as shown in the table below.

#### 4.3. Results

TESTS	TRAY	SURFACE RESISTANCE MEASUREMENTS (ohms)						
12313	SAMPLES	Point 1	Point 2	Point 3	Point 4	Point 5	Point 6	
	Sample 1	1.1E+06	8.6E+07	1.2E+08	1.6E+06	5.8E+07	1.1E+08	
	Sample 2	1.0E+07	1.3E+06	1.4E+08	1.2E+08	1.3E+09	2.3E+07	
SURFACE	Sample 3	1.3E+08	5.4E+06	1.1E+06	2.2E+06	8.6E+07	6.1E+07	
RESISTANCE TEST	Sample 4	1.0E+08	6.2E+07	6.1E+07	9.6E+07	3.2E+07	3.6E+06	
	Sample 5	1.2E+07	9.8E+07	6.8E+06	7.8E+07	3.5E+06	6.2E+07	
	Sample 6	4.1E+07	7.7E+06	9.9E+06	2.1E+06	7.7E+07	9.5E+06	
SURFACE RESISTANCE	Sample 1 (before scratching)	1.1E+08						
AFTER SCRATCHING	Sample 1 (After scratching)	2.8E+08						

All measurements are within ST Specification Limits.

## 5. Workability Test: Result: Accepted

Process Step	Machine	Samples size	Rejection criteria	Result
Cropping	ASM	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Tester	Synax 141	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Finishing	STI	540 units	Bend lead, package crack, tray is jamming when machine running	Pass

#### 6. FIT Analysis

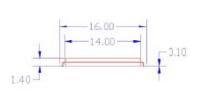
Result: Accepted

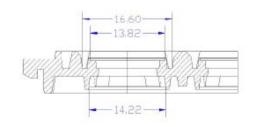
#### **Nominal Case:**

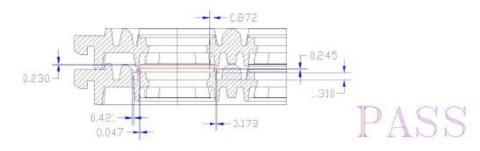
PKG. : STMicro(1L,8V,1B,4S,1S,TC,OS,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2

TRAY NOMINAL TYPICAL CONDITIONS





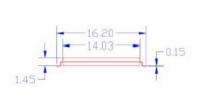


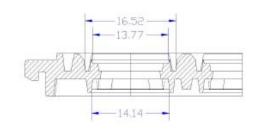
#### **Minimum Pocket vs Maximum Package:**

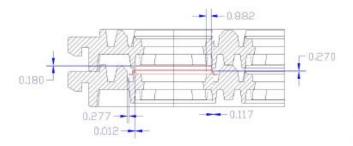
PKG.: STMicro(1L,8V,1B,4S,1S,TC,0S,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2

TRAY - MINIMUM - worst conditions (A)







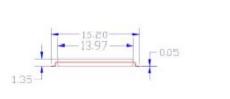
PASS

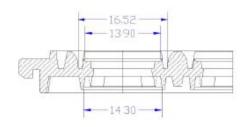
#### **Maximum Pocket vs Minimum Package:**

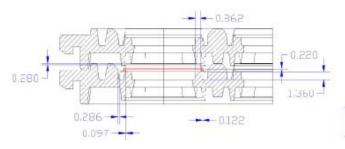
PKG. : STMicro(1L,8V,1B,4S,1S,TC,0S,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2

TRAY - MAXIMUM - WORST CONDITIONS (B)







PASS

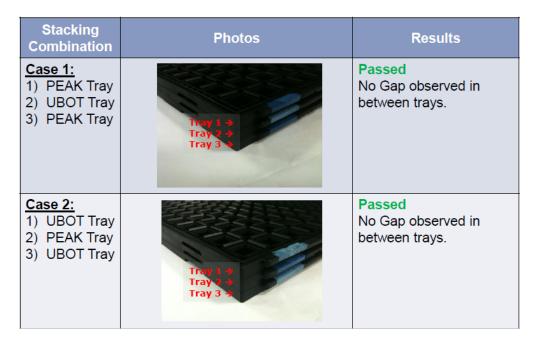
#### 7. Additional Items:

#### 7.1. Stackability Validation



A Tray	B Tray	Stackability
PEAK	ITW	Yes
ITW	PEAK	Yes

(i) PEAK trays are stackable with current source, ITW trays.



(ii) PEAK trays are stackable with alternative source, UBOT trays.

#### **Conclusion:**

With the above qualification results, PEAK (ND 1414 1.4 0615 6 REV.FbL2) tray passed all ST tray qualification requirements, thus, qualified for production use.

# **Qualification of PEAK TQFP 14x14x1.4 Tray**

#### **Objective:**

To evaluate PEAK (ND 1414 1.4 0615 6 REV.FbL2) trays as tray 2<sup>nd</sup> source for QFP 14x14x1.4 device packing application at PTM Malta.

#### **Tray Information:**

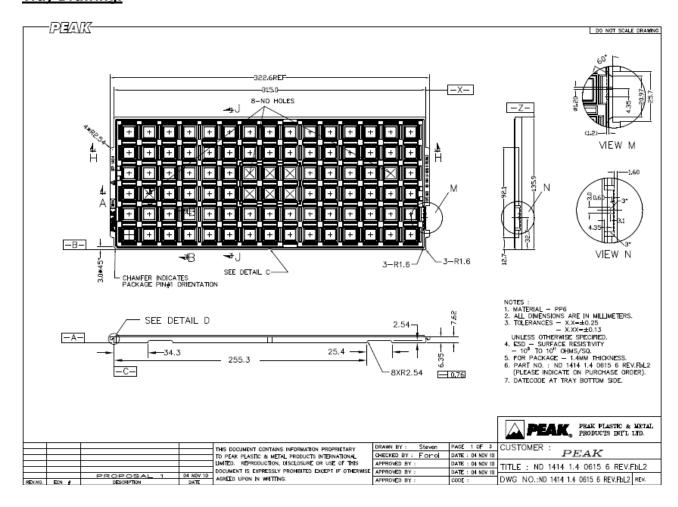
Supplier : PEAK

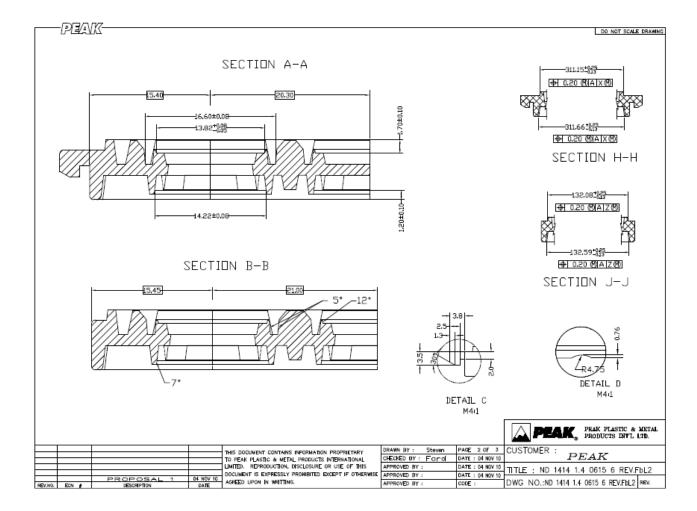
Supplier Part No : ND 1414 1.4 0615 6 REV.FbL2

Tray ADCS Reference No: 0004320

Material Code : 3CP20430/1 (Green/Blue Insert)

#### **Tray Drawing:**





## 1. Visual Inspection Report:

Result: Accepted. No Tray Abnormalities.

Items	Visual Inspection	Yes	No	Quantities	Remarks
1	Chip/Crack		Χ	N/A	
2	Align with ST Specification	Χ		N/A	
3	Tray Matrix	Χ		N/A	
4	Full Fence	Χ		N/A	
5	Meet JEDEC Standard requirement	Χ		N/A	
6	Contain stain or foreign material		Х	N/A	
7	Others (Please defined)		Х		

#### 2. Baking Tests (Bakeable trays only)

**Result: Accepted** 

#### 2.1. <u>3 Cycle Baking</u> Result: Accepted

#### 2.1.1. Methodology

- i) Sample: 10 trays.
- ii) Duration: 24 hrs for each cycle. After each cycle, the tray must leave at production environment for a minimum of 1 hr before starting the second baking.
- iii) Temperature: 125 deg.C (Refer to specification number 0033575)
- iv) Trays must strap using Velcro or PP (Polypropylene) belt. Strapping refers to specification number 0056593.
- v) Baking can be carrying out without units.
- vi) Measure the tray warpage after the 3<sup>rd</sup> cycle on all 6 corners as indicated in specification 8080190.
- vii) The war page should not be > 0.5mm for new tray.

#### 2.1.2. <u>Results</u>

Tray warpage after 3 cycle baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.05	0	0.05	0.05	0.05	0.05
Sample 2	0.05	0.05	0.05	0.05	0.05	0.05
Sample 3	0.05	0	0.05	0.05	0	0
Sample 4	0.05	0.05	0.05	0.05	0	0.05
Sample 5	0.1	0.05	0.05	0.05	0	0.05
Sample 6	0.05	0.05	0.1	0.1	0.05	0.05
Sample 7	0.1	0.05	0.1	0.1	0.05	0.05
Sample 8	0.05	0.05	0.1	0.2	0.05	0.05
Sample 9	0	0.1	0.1	0.05	0.1	0.45
Sample 10	0	0.1	0.05	0.1	0.1	0.55

All measurements were found to be below the 0.5mm (*maximum acceptable warpage as declared in document 8080190 rev E*), except for the 0.55mm, which was considered as limit case..

#### 2.2. Single Bake

**Result: Accepted** 

#### 2.2.1. Methodology

- i) Sample: 6 pieces of single trays not stacked.
- ii) Duration 48 hrs.
- iii) Temperature: Base on the temperature mark on the tray (150 deg.C)
- iv) Without unit and without strapping
- v) After single bake, the tray warpage is measured after leaving the tray to cool to room temperature.
- vi) Measure the tray warpage on all 6 corners as indicated in specification 8080190

#### 2.2.2. <u>Results</u>

Tray warpage after Single Baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0.05	0.15	0.05	0.05	0.05	0.05
Sample 2	0.1	0	0.1	0.05	0	0.05
Sample 3	0	0.5	0.1	0	0.1	0.05
Sample 4	0.1	0.05	0.05	0.05	0.05	0
Sample 5	0.1	0	0.05	0.05	0.05	0.05
Sample 6	0.15	0.05	0.05	0.05	0.05	0.1

The trays were also checked for the below items:

Items	Result
Any melting point on tray	NO
Any shrinkage on overall length	NO
Any shrinkage on overall thickness	NO
Any shrinkage on pocket dimension	NO
Maximum warpage from 6 corners	0.5mm
should not be more than 0.76mm	0.511111

### 3. Drop Test

Result: Accepted

#### 3.1. Methodology

The drop test was performed with the packing methodology described in specification number 0056593. The drop test was carried out according to methodology described in specification number 7416802.

#### 3.2. Results

Drop Test Sequence	Scanning Results for: i) Coplan ii) Standoff iii) Pitch	Results
ABC	0 rejects	Pass
DEF	0 rejects	Pass
GHI	0 rejects	Pass

Note: Drop Test Sequence ABC refers to Face A, Edge B & Corner C.

Inspection items	Sample size	Reject quantity for ABC	Reject quantity for DEF	Reject quantity for GHI
Unit chip	540 units	0/540	0/540	0/540
Unit stuck	540 units	0/540	0/540	0/540
Unit misplace	540 units	0/540	0/540	0/540
Chip trays	7 trays	0/7	0/7	0/7

#### 4. ESD Measurements

Result: Accepted.

#### 4.1. Equipment

- i) Prostat PRS-801 Resistance Meter
- ii) Prostat PRV-913 Microprobe Verifier
- iii) Prostat probes PRF-922A-B and PRF914
- iv) Prostat Psychrometer PHT-771

#### 4.2. Methodology

A sample of six trays were used to measure the surface resistance. Each tray was tested at six different points. The accepted limits for the trays should be within 1x10exp5<Rs<1x10exp11.

Every reading was recorded as shown in the table below.

#### 4.3. Results

TESTS	TRAY	SURFACE RESISTANCE MEASUREMENTS (ohms)							
IESIS	SAMPLES	Point 1	nt 1         Point 2         Point 3         Point 4         Point 5         F           8+08         6.0E+07         8.2E+07         5.7E+07         2.8E+07         1           8+07         5.8E+07         9.8E+07         5.1E+07         8.9E+06         3           8+07         5.4E+07         2.6E+08         3.5E+06         4.2E+06         1           8+07         1.1E+08         1.6E+08         2.4E+06         5.0E+07         1           8+08         1.2E+08         7.1E+07         4.2E+07         5.5E+06         7           8+07         1.7E+08         2.4E+08         1.1E+07         1.0E+07         2           8+08         1.0E+08         1.1E+07         1.0E+07         2	Point 6					
	Sample 1	1.3E+08	6.0E+07	8.2E+07	5.7E+07	2.8E+07	1.1E+07		
	Sample 2	9.2E+07	5.8E+07	9.8E+07	5.1E+07	8.9E+06	3.1E+07		
SURFACE	Sample 3	7.9E+07	5.4E+07	2.6E+08	3.5E+06	4.2E+06	1.4E+07		
RESISTANCE TEST	Sample 4	9.6E+07	1.1E+08	1.6E+08	2.4E+06	5.0E+07	1.3E+07		
	Sample 5	1.1E+08	1.2E+08	7.1E+07	4.2E+07	5.5E+06	7.5E+06		
	Sample 6	5.1E+07	1.7E+08	2.4E+08	1.1E+07	1.0E+07	2.6E+07		
SURFACE RESISTANCE	Sample 1 (before scratching)	1.6E+08							
AFTER SCRATCHING	Sample 1 (After scratching)	2.8E+08							

All measurements are within ST Specification Limits.

# 5. Workability Test: Result: Accepted

Process Step	Machine	Samples size	Rejection criteria	Result
Cropping	ASM MP209	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Tester	Multitest 9510	540 units	Bend lead, package crack, tray is jamming when machine running	Pass
Finishing	Hexa Whizz	540 units	Bend lead, package crack, tray is jamming when machine running	Pass

# 6. FIT Analysis

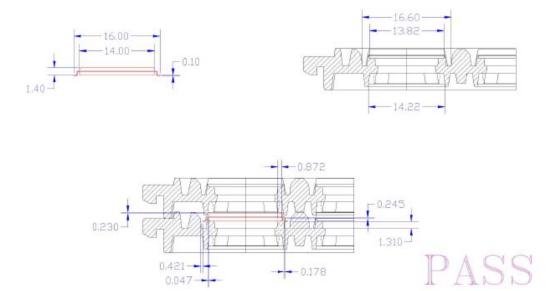
Result: Accepted

#### **Nominal Case:**

PKG.: STMicro(1L,8V,1B,4S,1S,TC,OS,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2

TRAY - NOMINAL - TYPICAL CONDITIONS

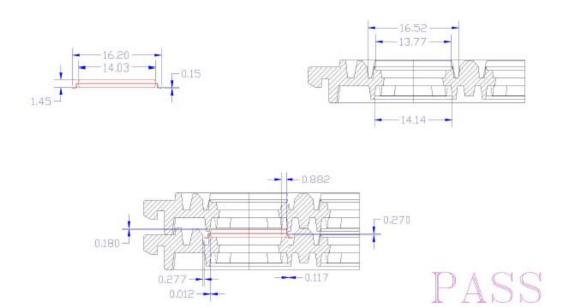


## Minimum Pocket vs Maximum Package:

PKG.: STMicro(1L,8V,1B,4S,1S,TC,OS,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2

TRAY - MINIMUM - worst conditions (a)

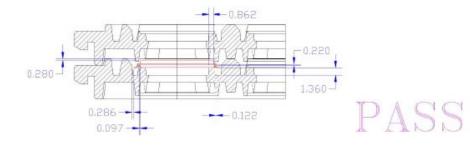


# **Maximum Pocket vs Minimum Package:**

PKG.: STMicro(1L,8V,1B,4S,1S,TC,OS,HG,FV,1R,9H,GF,MT)

TRAY: ND 1414 1.4 0615 6 REV.EbL2





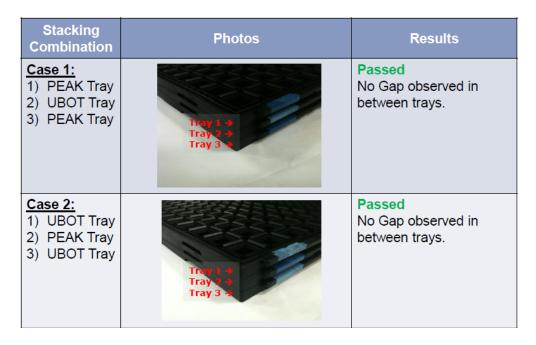
#### 7. Additional Items:

#### 7.1. Stackability Validation



A Tray	B Tray	Stackability
PEAK	ITW	Yes
ITW	PEAK	Yes

(i) PEAK trays are stackable with current source, ITW trays.



(ii) PEAK trays are stackable with alternative source, UBOT trays.

#### **Conclusion:**

With the above qualification results, PEAK (ND 1414 1.4 0615 6 REV.FbL2) tray passed all ST tray qualification requirements, thus, qualified for production use.

# **Qualification of PEAK PQFP 28x28 Tray**

#### **Objective:**

To evaluate PEAK (ND2828 3.5 0308 6 REV.GbL2) trays as tray 2<sup>nd</sup> source for PQFP 28x28 device packing application at PTM Malta.

#### **Tray Information:**

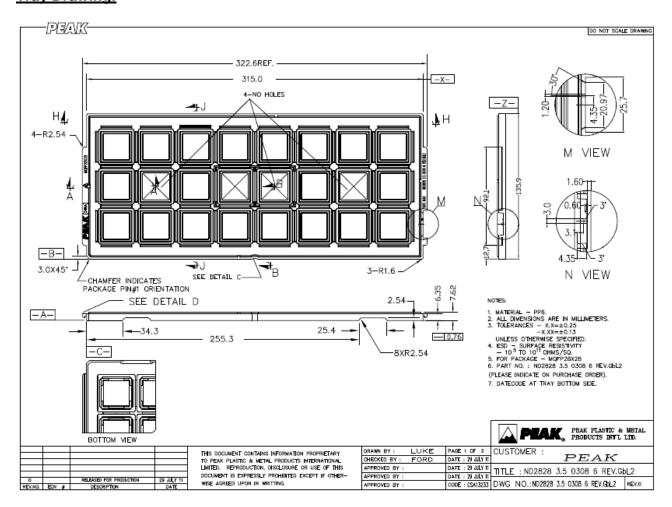
Supplier : PEAK

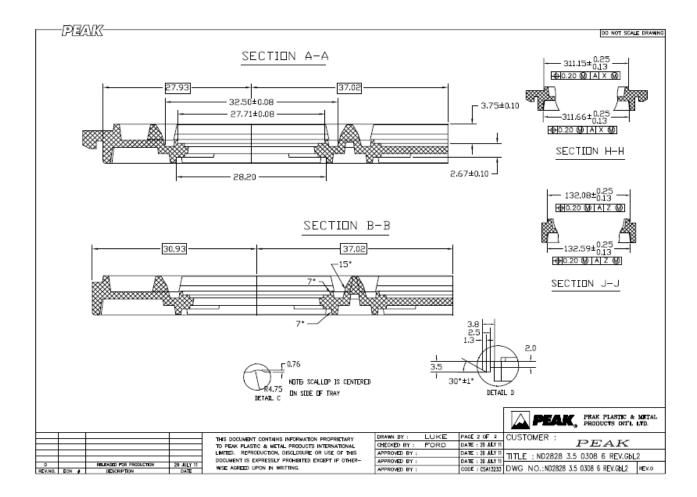
Supplier Part No : ND2828 3.5 0308 6 REV.GbL2

Tray ADCS Reference No: 0105455

Material Code : 3CP10251/3CP70910 (Green/Blue Insert)

#### **Tray Drawing:**





# 1. Visual Inspection Report:

Result: Accepted. No Tray Abnormalities.

Items	Visual Inspection	Yes	No	Quantities	Remarks
1	Chip/Crack		X	N/A	
2	Align with ST Specification	Χ		N/A	
3	Tray Matrix	Χ		N/A	
4	Full Fence	Χ		N/A	
5	Meet JEDEC Standard requirement	Х		N/A	
6	Contain stain or foreign material		X	N/A	
7	Others (Please defined)		Х		

#### 2. Baking Tests (Bakeable trays only)

**Result: Accepted** 

#### 2.1. <u>3 Cycle Baking</u> Result: Accepted

#### 2.1.1. Methodology

- i) Sample: 10 trays.
- ii) Duration: 24 hrs for each cycle. After each cycle, the tray must leave at production environment for a minimum of 1 hr before starting the second baking.
- iii) Temperature: 125 deg.C (Refer to specification number 0033575)
- iv) Trays must strap using Velcro or PP (Polypropylene) belt. Strapping refers to specification number 0056593.
- v) Baking can be carrying out without units.
- vi) Measure the tray warpage after the 3<sup>rd</sup> cycle on all 6 corners as indicated in specification 8080190.
- vii) The warpage should not be > 0.5mm for new tray.

#### 2.1.2. <u>Results</u>

Tray warpage after 3 cycle baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0	0.3	0	0	0.3	0
Sample 2	0	0.3	0	0	0.2	0
Sample 3	0	0.2	0	0	0.15	0.05
Sample 4	0	0.15	0	0	0.15	0
Sample 5	0	0.2	0	0	0.15	0
Sample 6	0	0.2	0	0	0.2	0
Sample 7	0	0.25	0	0	0.15	0
Sample 8	0	0.3	0	0	0.15	0
Sample 9	0	0.2	0	0	0.15	0
Sample 10	0	0.2	0	0	0.15	0

All readings are within limits

#### 2.2. Single Bake

**Result: Accepted** 

#### 2.2.1. Methodology

- i) Sample: 6 pieces of single trays not stacked.
- ii) Duration 48 hrs.
- iii) Temperature: Base on the temperature mark on the tray (150 deg.C)
- iv) Without unit and without strapping
- v) After single bake, the tray warpage is measured after leaving the tray to cool to room temperature.
- vi) Measure the tray warpage on all 6 corners as indicated in specification 8080190

#### 2.2.2. <u>Results</u>

Tray warpage after Single Baking test:

Warpage (mm)	Side 1	Side 2	Side 3	Side 4	Side 5	Side 6
Sample 1	0	0.55	0	0	0.3	0.05
Sample 2	0	0.4	0	0	0.2	0
Sample 3	0	0.4	0	0	0.4	0
Sample 4	0	0.5	0	0	0.45	0
Sample 5	0	0.5	0	0	0.45	0
Sample 6	0	0.5	0	0.05	0.45	0

The trays were also checked for the below items:

Items	Result	
Any melting point on tray	NO	
Any shrinkage on overall length	NO	
Any shrinkage on overall thickness	NO	
Any shrinkage on pocket dimension	NO	
Maximum warpage from 6 corners	0.55mm	
should not be more than 0.76mm		

#### 3. Drop Test

Result: Accepted

#### 3.1. Methodology

The drop test was performed with the packing methodology described in specification number 0056593. The drop test was carried out according to methodology described in specification number 7416802.

#### 3.2. Results

Drop Test Sequence	Scanning Results for: i) Coplan ii) Standoff iii) Pitch	Results
ABC	0 rejects	Pass
DEF	0 rejects	Pass
GHI	0 rejects	Pass

Note: Drop Test Sequence ABC refers to Face A, Edge B & Corner C.

Inspection items	Sample size	Reject quantity for ABC	Reject quantity for DEF	Reject quantity for GHI
Unit chip	240 units	0/240	0/240	0/240
Unit stuck	240 units	0/240	0/240	0/240
Unit misplace	240 units	0/240	0/240	0/240
Chip trays	11 trays	0/11	0/11	0/11

#### 4. ESD Measurements

Result: Accepted.

#### 4.1. Equipment

- i) Prostat PRS-801 Resistance Meter
- ii) Prostat PRV-913 Microprobe Verifier
- iii) Prostat probes PRF-922A-B and PRF914
- iv) Prostat Psychrometer PHT-771

#### 4.2. Methodology

A sample of six trays were used to measure the surface resistance. Each tray was tested at six different points. The accepted limits for the trays should be within 1x10exp5<Rs<1x10exp11.

Every reading was recorded as shown in the table below.

#### 4.3. Results

TESTS	TRAY SAMPLES	SURFACE RESISTANCE MEASUREMENTS (ohms)			
		Point 1	Point 2	Point 3	Point 4
SURFACE RESISTANCE TEST	Sample 1	2.9e9	2.8e6	1.2e9	3.9e9
	Sample 2	2.2e9	4.0e7	2.6e9	1.9e9
	Sample 3	2.0e9	5.4e6	1.4e9	2.8e9
	Sample 4	7.6e8	6.9e6	2.7e9	2.8e9
	Sample 5	1.3e9	1.9e7	3.1e9	3.2e9
	Sample 6	1.3e9	5.3e6	2.2e9	3.8e9
SURFACE RESISTANCE AFTER SCRATCHING	Sample 1 (before scratching)	1.8e8			
	Sample 1 (After scratching)	9.8e7			

All measurements are within ST Specification Limits.

### 5. Workability Test: Result: Accepted

Process Step	Machine	Samples size	Rejection criteria	Result
Cropping	Fico TFM UF	240 units	Bend lead, package crack, tray is jamming when machine running	Pass
Tester	Multitest 9510	240 units	Bend lead, package crack, tray is jamming when machine running	Pass
Finishing	Hexa Whizz	240 units	Bend lead, package crack, tray is jamming when machine running	Pass

# 6. FIT Analysis

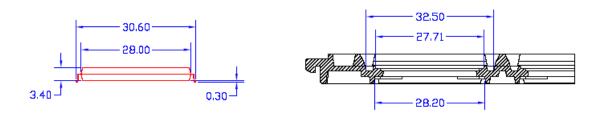
Result: Accepted

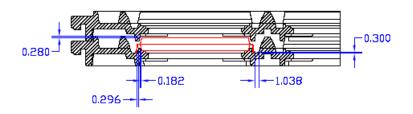
PKG.: ST-Micro 0120082 CODE 5R

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - NOMINAL TYPICAL CONDITIONS

PKG - NOMINAL TYPICAL CONDITIONS



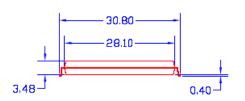


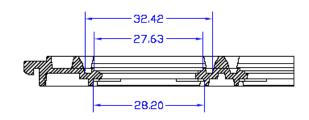
**PASS** 

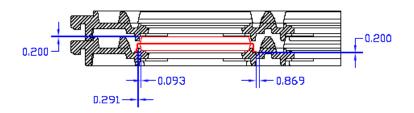
PKG.: ST-Micro 0120082 CODE 5R

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - MINIMUM-WORST CONDITIONS (A) PKG - MAXIMUM







# **PASS**

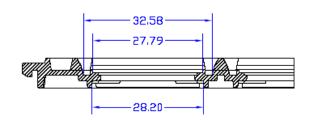
PKG.: ST-Miero 0120082 CODE 5R

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - MAXIMUM WORST CONDITIONS (B)

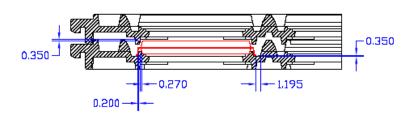
PKG - MINIMUM -





Date : Nov 08 2010

Simulated by Haley

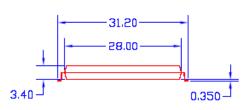


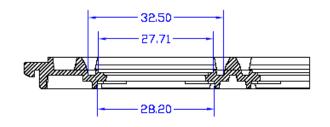
**PASS** 

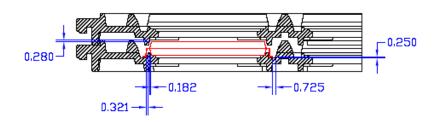
PKG.: ST-Micro 0060668/C CODE 5M

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - NOMINAL TYPICAL CONDITIONS





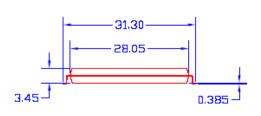


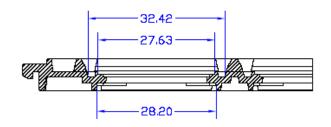
# **PASS**

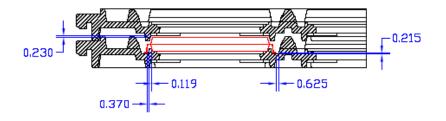
PKG.: ST-Micro 0060668/C CODE 5M

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - MINIMUM - WORST CONDITIONS (A)







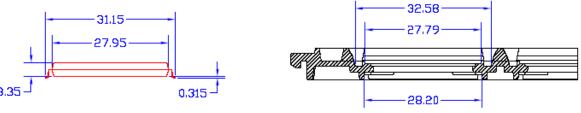
**PASS** 

PKG.: ST-Miero 0060668/C CODE 5M

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

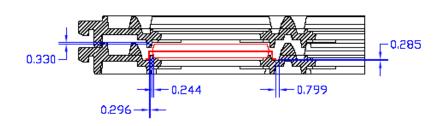
TRAY - MAXIMUM - worst conditions (B)





Date : Nov 08 2010

Simulated by Haley



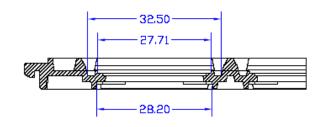
**PASS** 

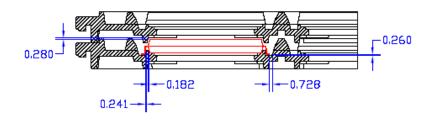
PKG.: ST-Micro 0060667/C CODE 5L

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - NOMINAL TYPICAL CONDITIONS





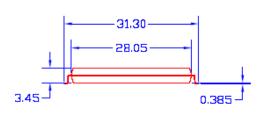


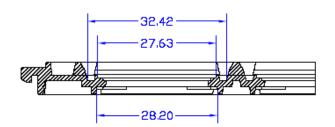
# **PASS**

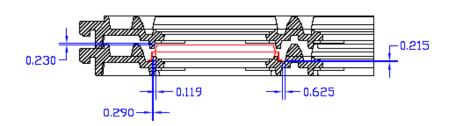
PKG.: ST-Micro 0060667/C CODE 5L

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - MINIMUM - WORST CONDITIONS (A)







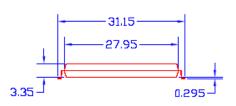
**PASS** 

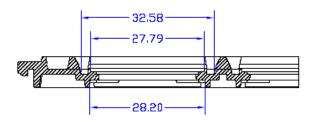
PKG. : ST-Miero 0060667/C CODE 5L

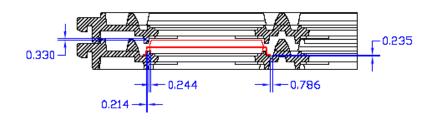
TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

Date : Nov 08 2010 Simulated by Haley

TRAY - MAXIMUM - WORST CONDITIONS (B)





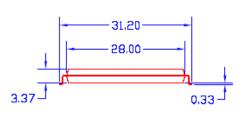


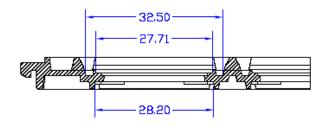
**PASS** 

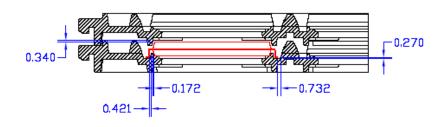
PKG.: ST-Micro 0060665/B

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - NOMINAL - TYPICAL CONDITIONS





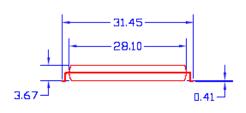


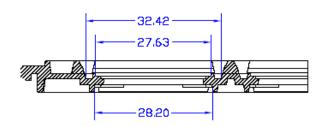
# **PASS**

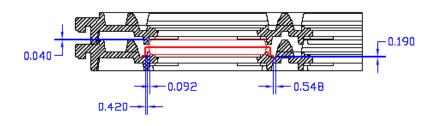
PKG. : ST-Micro 0060665/B

TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

TRAY - MINIMUM - WORST CONDITIONS (A)







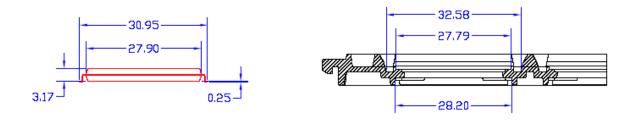
PKG. : ST-Miero 0060665/B

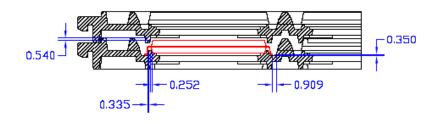
TRAY: DAEWON NEW 1st DESIGN (MQFP 28X28mm)

Simulated by Haley

Date: Nov 08 2010

TRAY - MAXIMUM - WORST CONDITIONS (B)





**PASS** 

## **Conclusion:**

With the above qualification results, PEAK (ND2828 3.5 0308 6 REV.GbL2) tray passed all ST tray qualification requirements, thus, qualified for production use.

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